



Millisecond flash lamp treatment for Nb-compounds and SRF accelerating cavities

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Helmholtz-Zentrum Dresden-Rossendorf (HZDR)

Dresden



Dresden

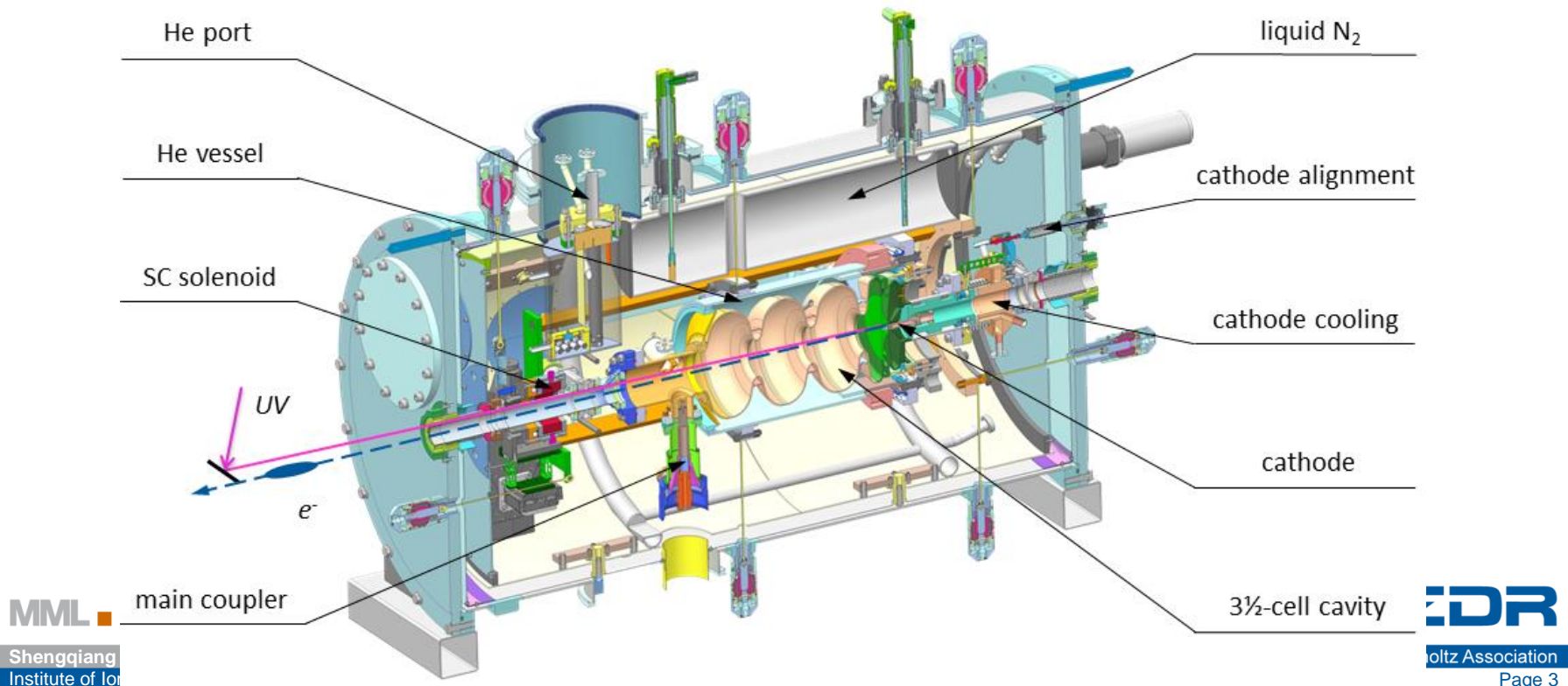


Helmholtz-Zentrum Dresden-Rossendorf (HZDR)

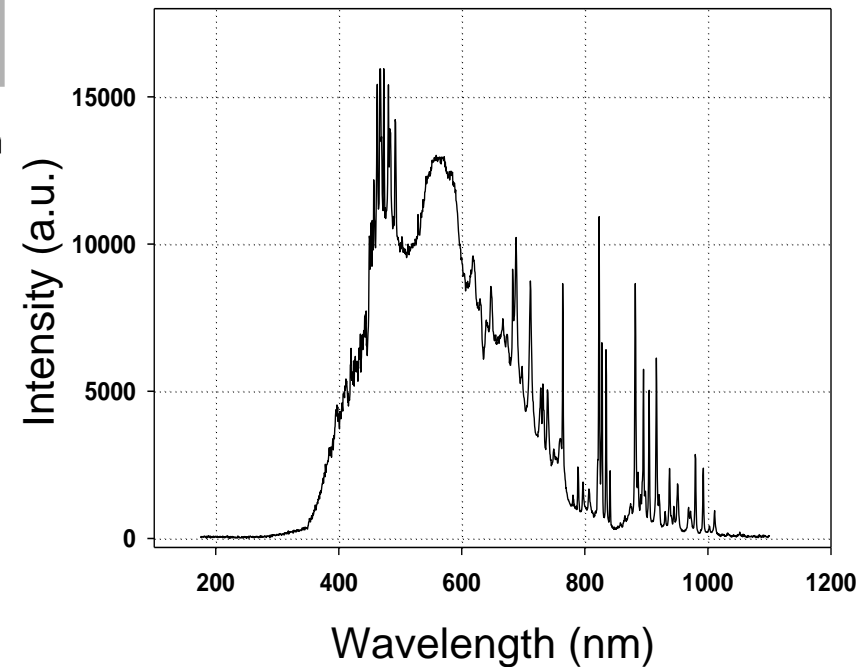
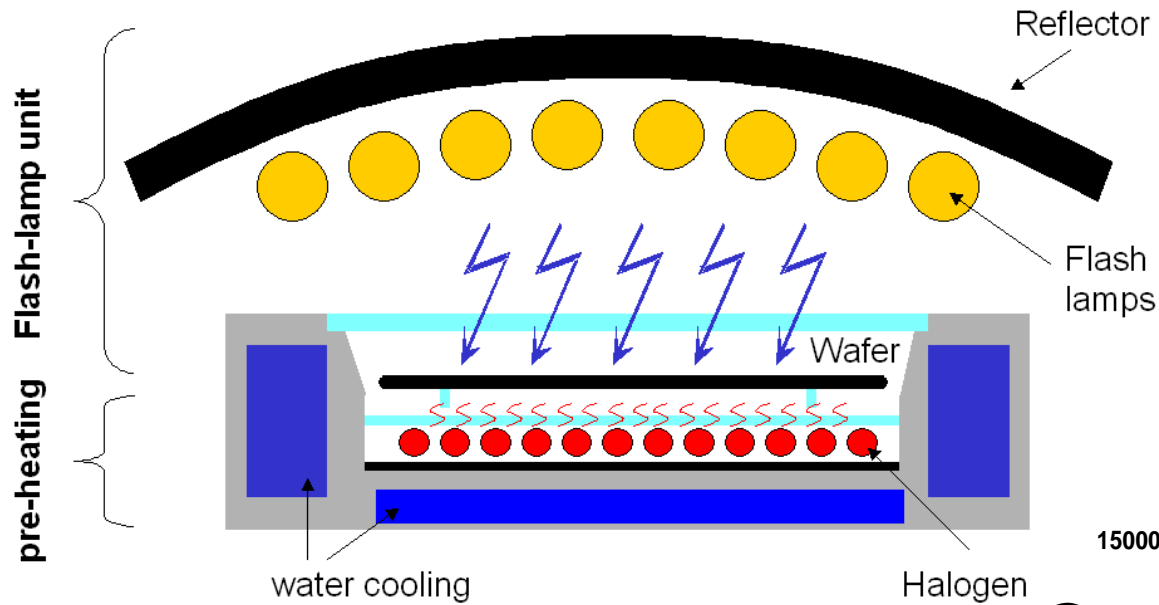
R. Xiang, et al., [SRF Gun and SRF Linac Driven THz at ELBE Successfully in User Operation](#), 19th International Conference on RF Superconductivity (SRF 2019)

J. Teichert, et al., [Successful user operation of a superconducting radio-frequency photoelectron gun with Mg cathodes](#), Phys. Rev. Accel. Beams 24, 033401 (2021)

2021: selected component for LCLS-II-HE



Material processing: flash lamp annealing



Thermal processing of semiconductors

Laser

FLA

RTA

FA

ns

ms

s

min-h

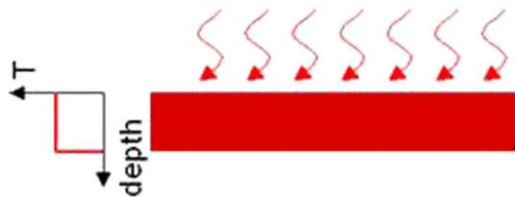


ultra-short annealing



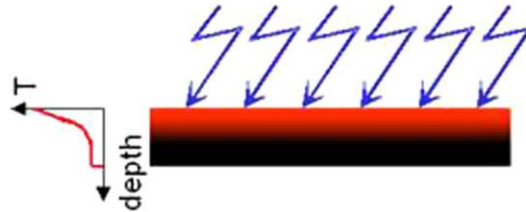
Millisecond-flash-lamp-annealing (FLA)

RTP



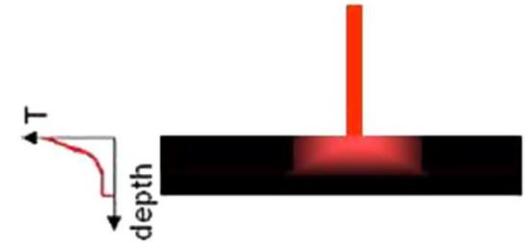
- whole wafer heated
- $T_{RS} \approx T_{FS}$
- 1 – 100 s
- up to 1300°C
- halogen lamps
- broad spectrum
~ 800 nm
- one shot-one wafer

FLA



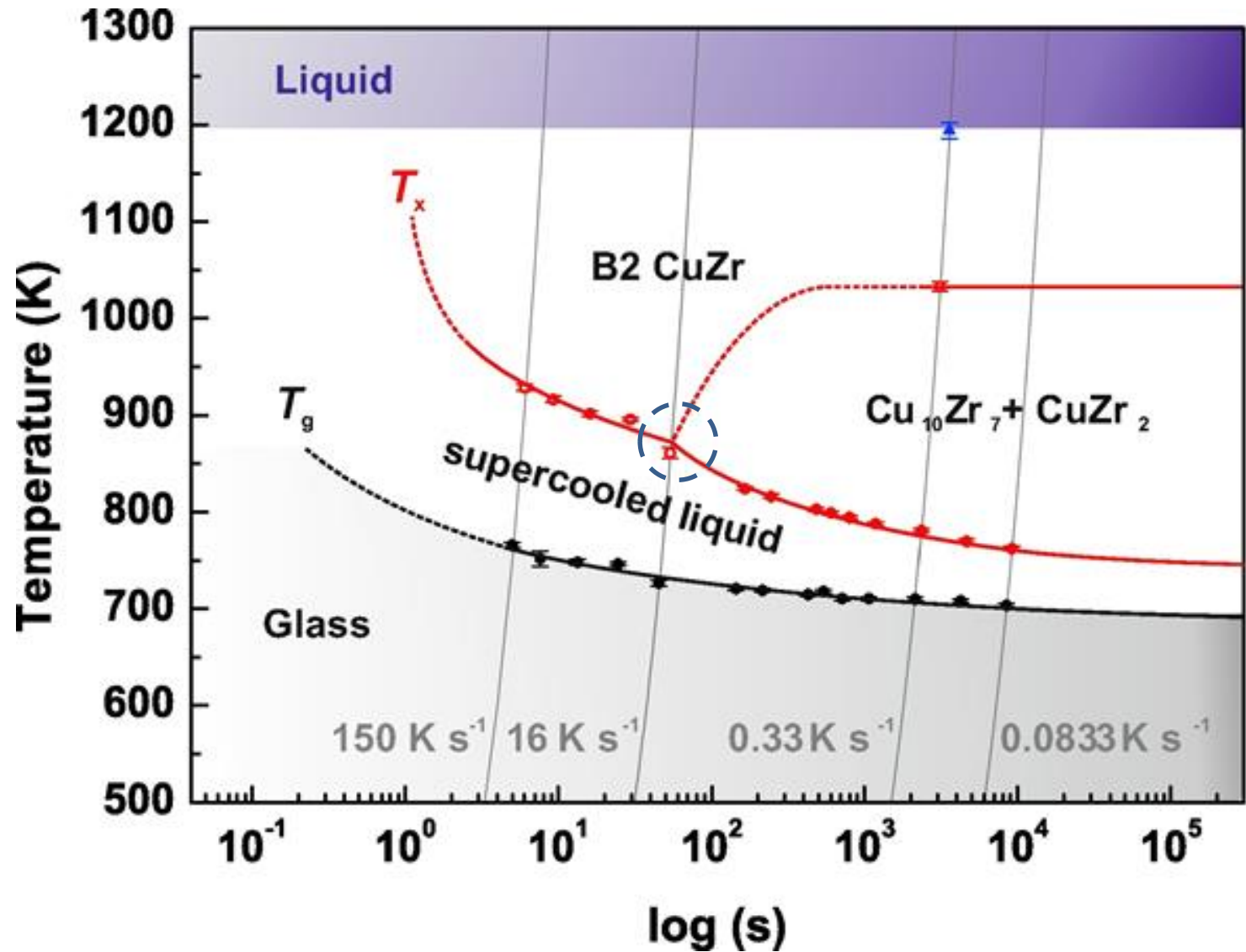
- only surface heated
- $T_{RS} \ll T_{FS}$
- 0.5 – 20 ms
- up to 2000°C
- Xe flash lamp
- broad spectrum
~ 400 nm
- one shot-one wafer

Laser



- only surface heated
- $T_{RS} \ll T_{FS}$
- 1 – 1000 ns, ms for cw
- up to 2000°C
- XeCl excimer (308 nm)
KrF excimer (248 nm)
- discrete lines
(interference effects!)
- point or line scan

Selected phase formation



Kosiba, K. et al. *Acta Mater.* 127, 416–425 (2017).

Z. Li and S. Zhou, et al. *Adv. Funct. Mater.* 15, 2009723 (2021).

Nb₃Sn, NbN on Cu by Sputtering

- **Similar to Nb on Cu cavities**
- **Solve the Low Thermal Conductivity issue of Nb substrate**
- **A first prototype of 1.3 GHz cavity is under developing in iFAST WP9**
- **Low melting point of Cu is a limitation**
- **650 °C can be considered a limit in a Cu cavity**
- **Diffusion of Cu into Nb₃Sn**

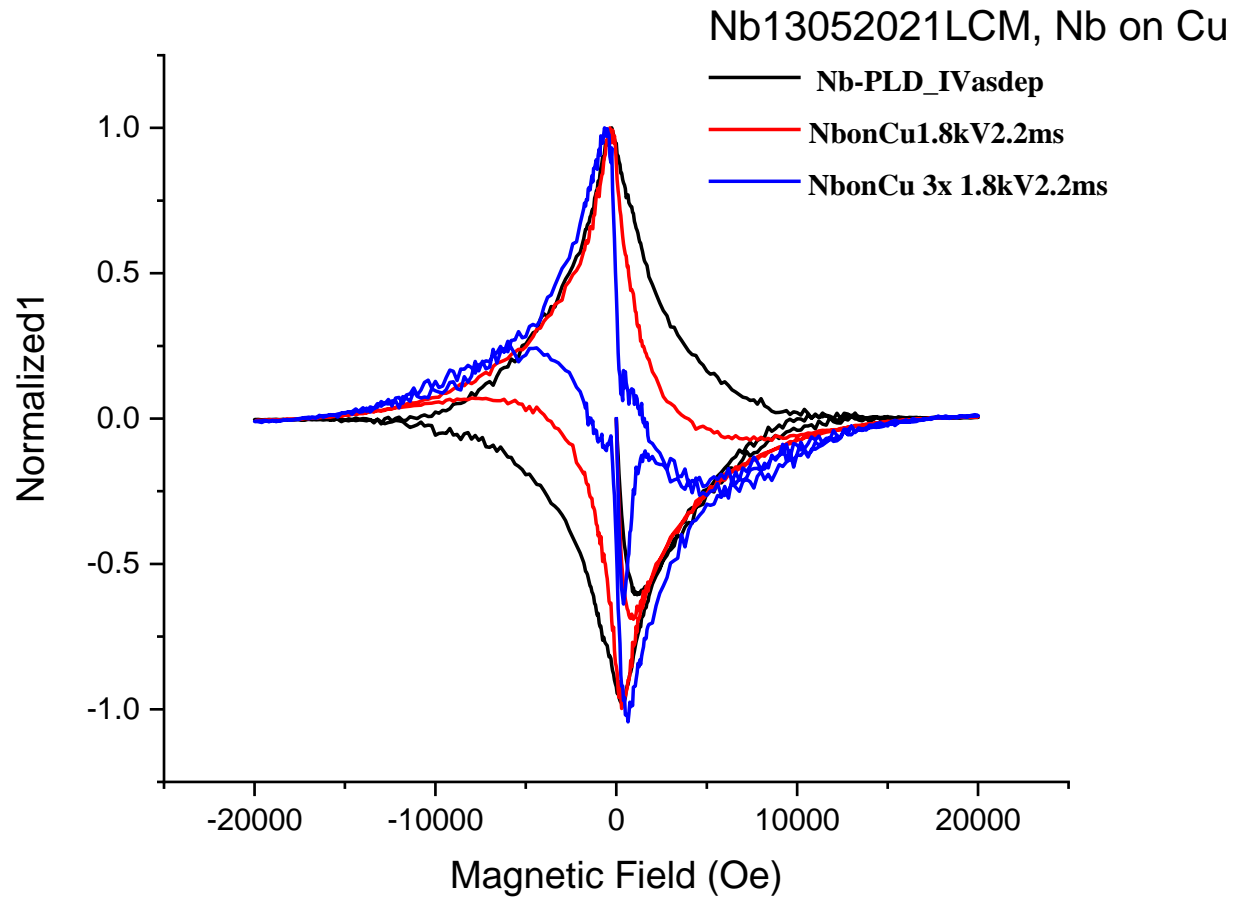


6 GHz Nb on Cu Cavity @LNL

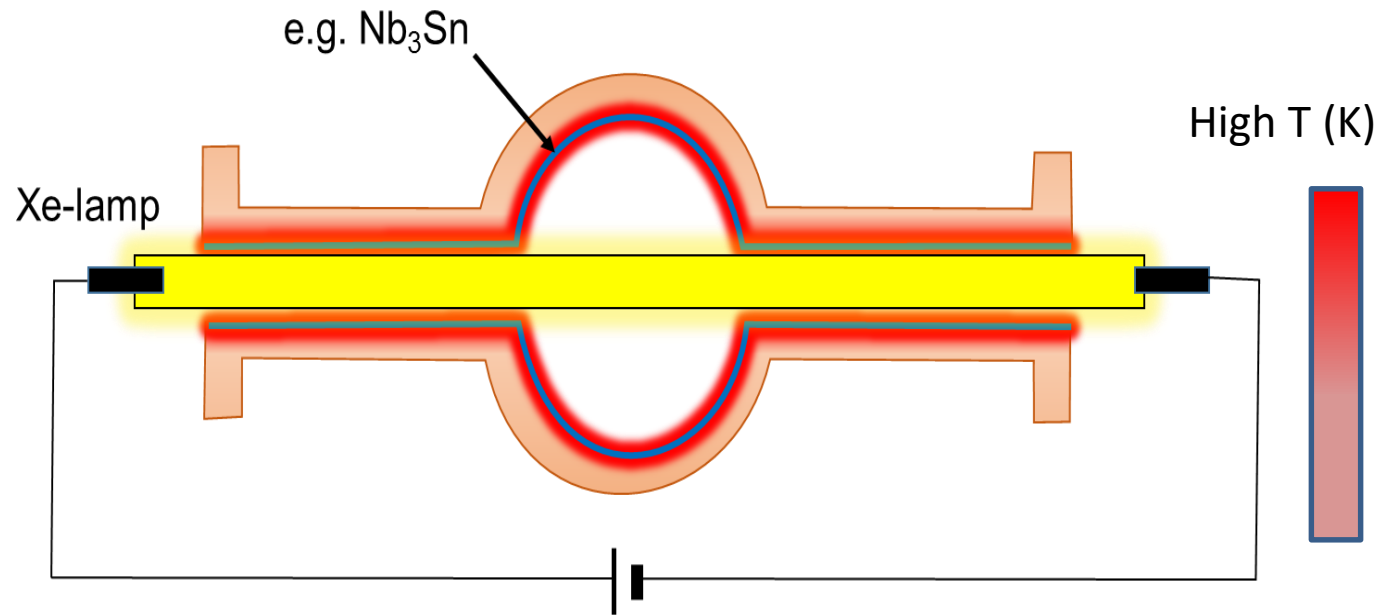
From Cristia Pira, INFN

First try for Nb on Cu

Nb13052021LCM, Nb on Cu



Easy extended to cavity size



Temperature distribution
in flashed cavity 20 ms

From Cristian Pira, INFN

Materials characterization

magnetic and electrical



SQUID-VSM
Lakeshore Hall Measurement system
1.8-400 K
up to 7 T



Raman, RBS, Positron

Materials characterization

RBS/PIXE: composition, trace impurities

Rutherford backscattering

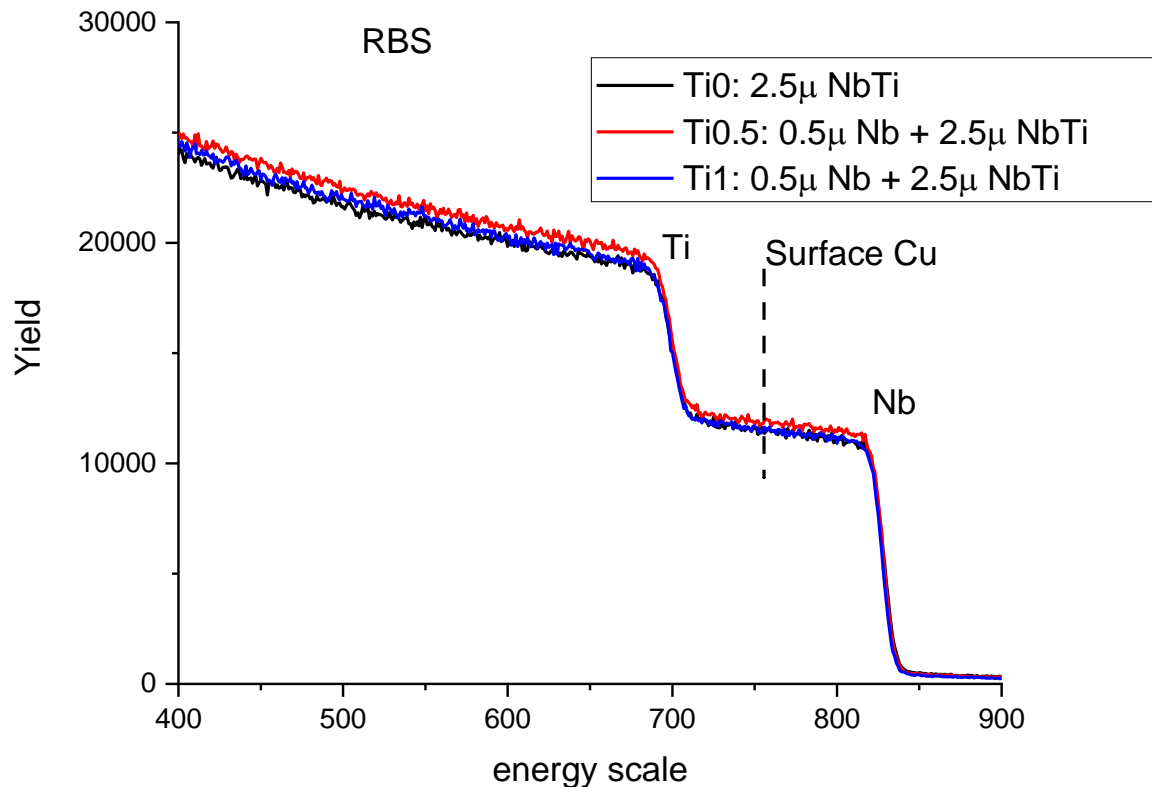
Rutherford backscattering Spectrometry

**From a method to understand the matter
to a method for materials research**

- (1) Identify the element and its concentration
- (2) Depth profile of concentration in thin film

Materials characterization

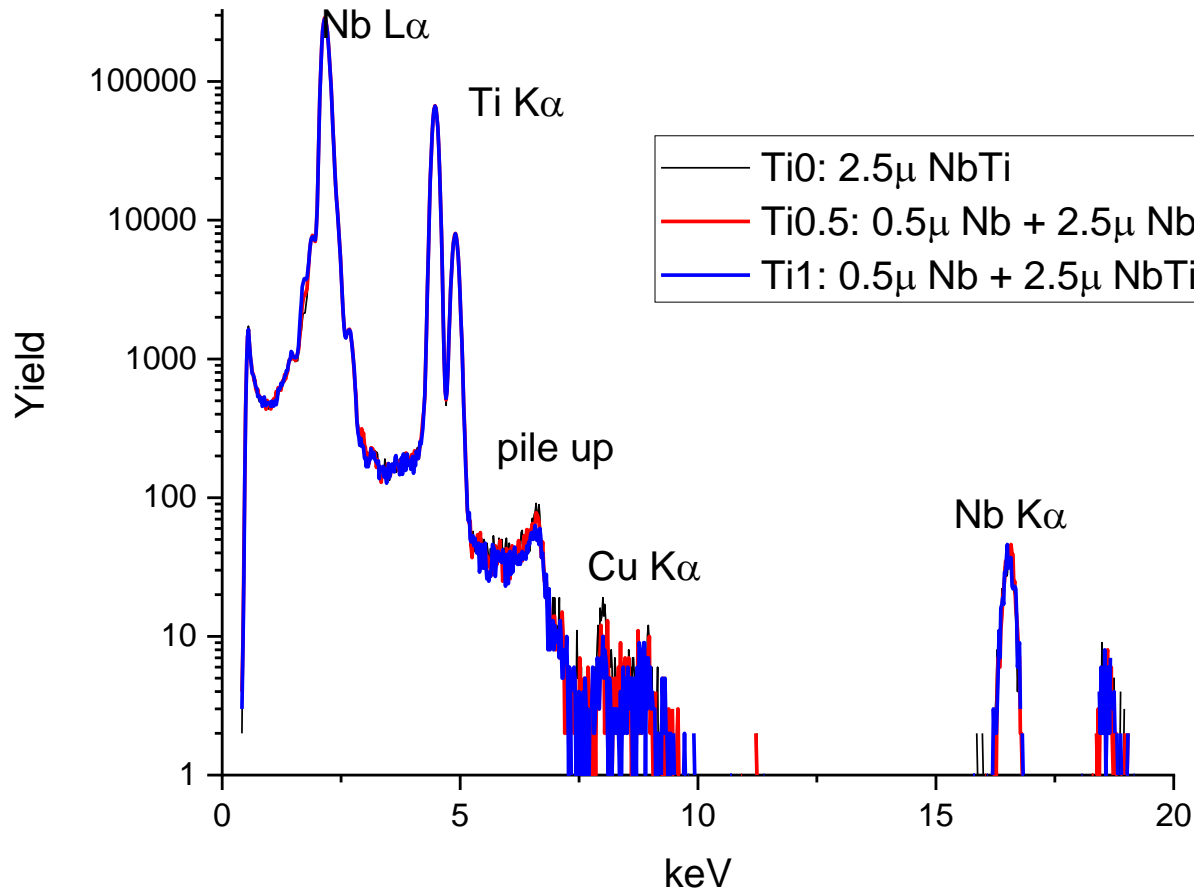
RBS/PIXE: composition, trace impurities



Samples From Cristian Pira, INFN

Materials characterization

RBS/PIXE: composition, trace impurities

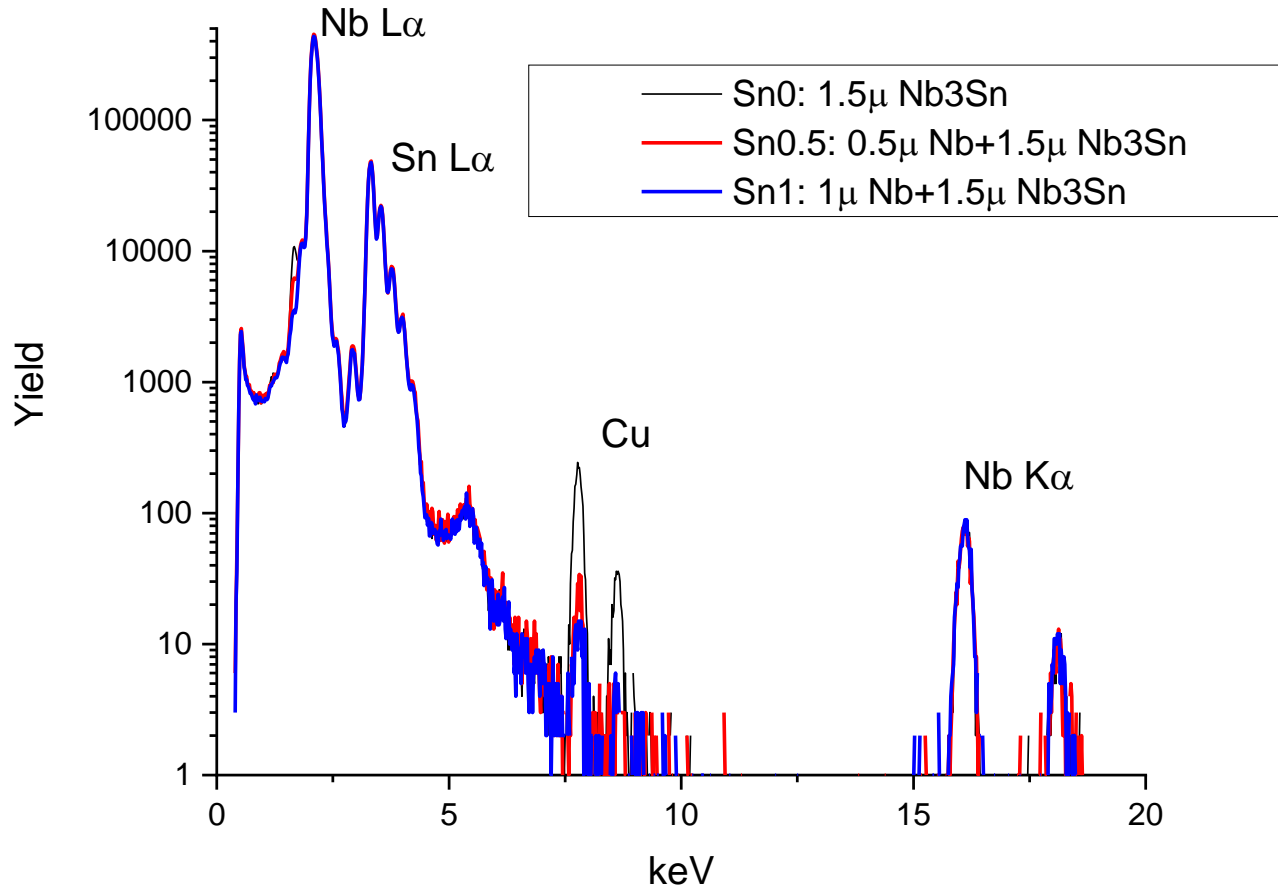


The weak Cu signal is from the substrate since the top layer is too thin. The He particle excites the Cu from the substrate.

MMI IN-HOUSE RESEARCH *Samples From Cristia Pira, INFN*

Materials characterization

RBS/PIXE: composition, trace impurities

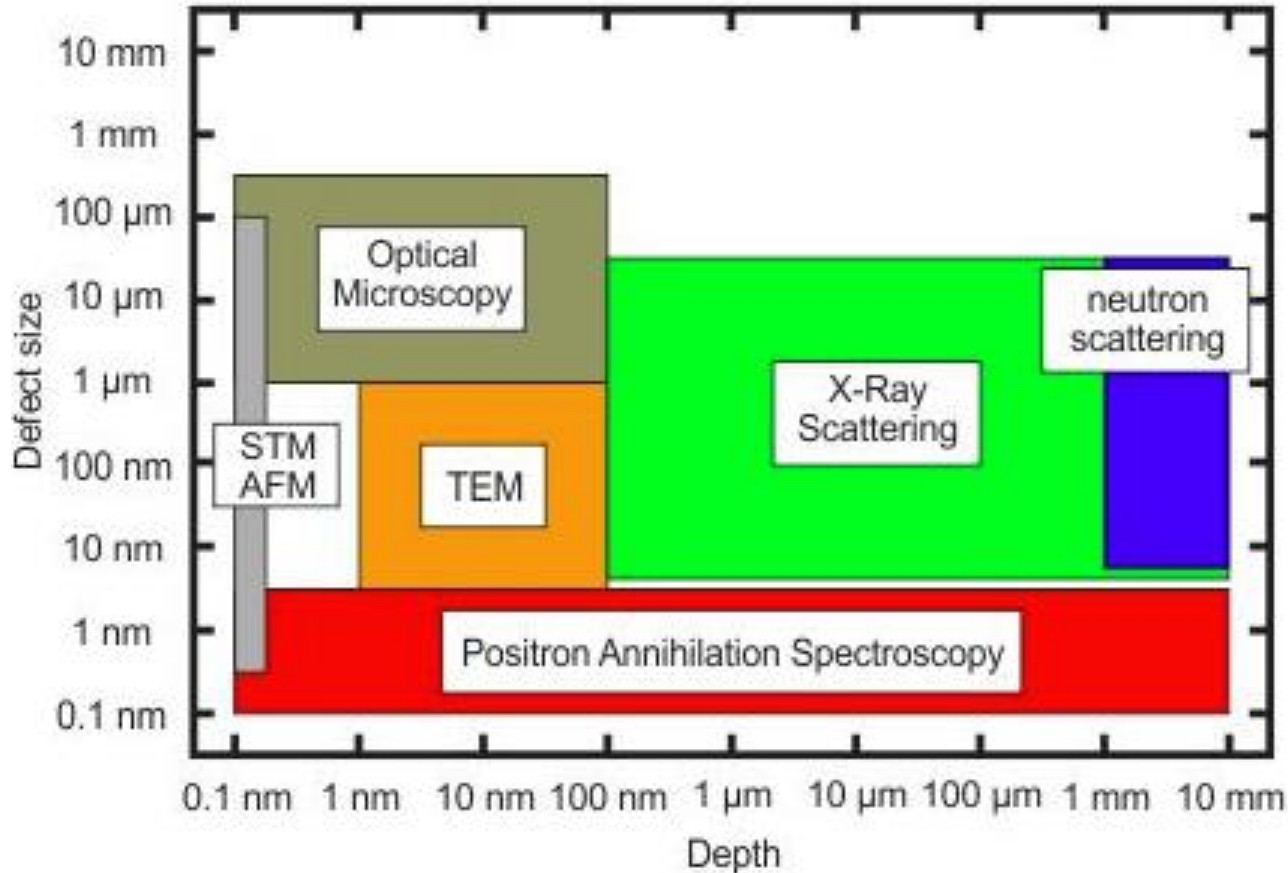


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MMI IN-HOUSE RESEARCH *Samples From Cristian Pira, INFN*

Materials characterization

Positron annihilation lifetime

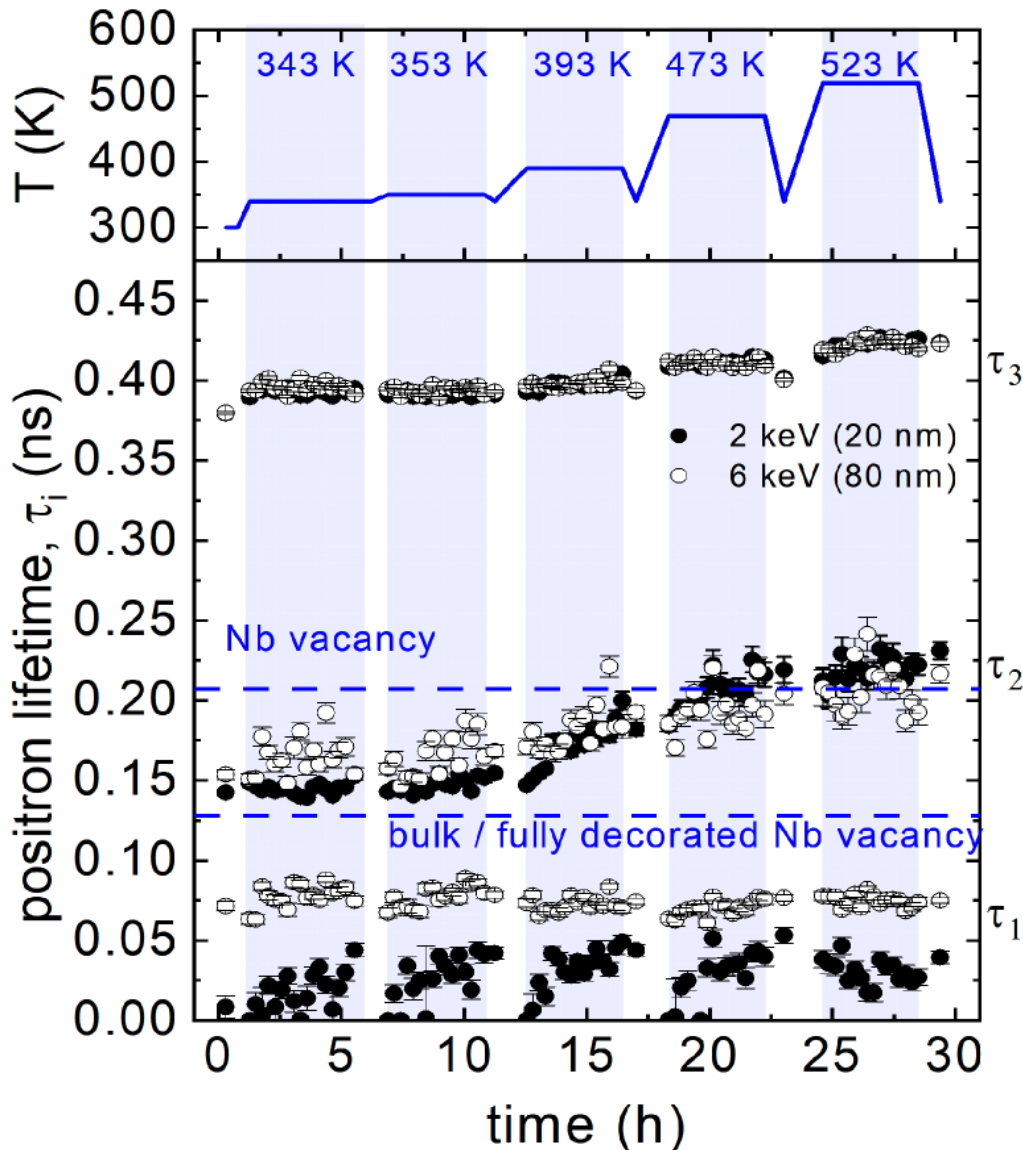


Open volume defects
Vacancy or vacancy cluster

- Single vacancy:
Shorter life time
- Vacancy cluster:
Longer life time

Materials characterization

Positron annihilation lifetime



Vacancy dynamics in niobium and its native oxides and their potential implications for quantum computing and superconducting accelerators
Phys. Rev. B 106, 094516 (2022)

Next step

- (1) Flash lamp processing Nb₃Sn and NbN, ...
- (2) Thin film characterization
- (3) Design FLA system for cavity